ment (for structure determination), while for some crystals with only moderate mosaic spread such data collection will be practicable.

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# One-Wavelength Technique: Estimation of Centrosymmetrical Two-Phase Invariants in Dispersive Structures 

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#### Abstract

Two-phase structure invariants of type $\Phi=\varphi_{\mathbf{h}}+\varphi_{-\mathrm{h}}$ are estimated in centrosymmetrical space groups, and in non-centrosymmetrical ones when $\varphi_{h}$ is a sym-metry-restricted phase. The distributions are of von Mises type with concentration parameters half those occurring in non-centric distributions.


## Notation

$N$ number of atoms in the unit cell $t$ number of atoms in the asymmetric unit
$f=f^{\prime}+i f^{\prime \prime}$ general expression for the atomic scattering factor
$\left.F^{+}=A^{+}+i B^{+}\right\}$structure factors of the reflexions
$\left.F^{-}=A^{-}+i B^{-}\right\} \quad h$ and -h respectively
$\varphi^{+}, \varphi^{-}$phases of $F^{+}, F^{-}$
$\mathbf{C}_{S} \equiv\left(\mathbf{R}_{S}, \mathbf{T}_{S}\right) \quad$ Sth symmetry operator: $\mathbf{R}_{S}$ is the rotational part, $\mathbf{T}_{S}$ the translational part
$\xi_{j}=\sum_{s=1}^{m} \cos 2 \pi h\left(\mathbf{R}_{s} \mathbf{r}_{j}+\mathbf{T}_{S}\right)$
$\eta_{j}=\sum_{s=1}^{m} \sin 2 \pi h\left(\mathbf{R}_{s} \mathbf{r}_{j}+\mathbf{T}_{s}\right)$
$\varepsilon_{h}$ Wilson's (1980) statistical weight of the reflection $h$ $\sum_{+}=\varepsilon \sum_{j=1}^{N}\left(f_{j}^{\prime 2}+f_{j}^{\prime \prime 2}\right) \quad$ average value of $\left|F_{\mathbf{h}}\right|^{2}$ at given $|\mathbf{h}|$ $\sum_{-}=\varepsilon \sum_{j=1}^{N}\left(f_{j}^{\prime 2}-f_{j}^{\prime \prime 2}\right)$
$R=F / \sum_{+}^{1 / 2}$ normalized modulus of the structure factor $D_{1}(x)=I_{1}(x) / I_{0}(x)$ ratio of modified Bessel functions of order 1 and 0
cs, ncs centrosymmetric, non-centrosymmetric

## 1. Introduction

Probabilistic approaches have been applied by several authors to crystal structures with dispersive atoms
(see Srinivasan \& Parthasarathy, 1976, and literature there quoted; Kroon, Spek \& Krabbendam, 1977; Heinerman, Krabbendam, Kroon \& Spek, 1978). Among the most recent results connected with this paper we quote:
(a) estimation of two-phase and three-phase structure invariants (Hauptman, 1982; Giacovazzo, 1983);
(b) estimation of probabilistic coefficients for a Patterson synthesis devoted to finding the positions of anomalous scatterers (Cascarano \& Giacovazzo, 1984);
(c) formulas estimating phases of the complete crystal structures when the position of the anomalous scatterers are known (Cascarano \& Giacovazzo, 1985).

Probabilistic treatment of the anomalous dispersion effect is more important in ncs space groups: accordingly all the approaches (a), (b), (c) were described in Cascarano \& Giacovazzo (1985). It is, however, of non-negligible interest to apply probabilistic methods for the estimation of the structure invariants in cs space groups, or in ncs space groups when the invariants are constituted by symmetryrestricted phases. This paper is devoted to the estimation of two-phase structure invariants in the above conditions. For the sake of brevity we give here only the final formulas: for the mathematical approach the reader is referred to a recent book (Giacovazzo, 1980).

## 2. The estimation of $\Phi=\varphi_{\mathrm{h}}+\varphi_{-\mathrm{h}}$ in centrosymmetric crystals

In cs space groups $F^{+} \equiv F^{-}$: thus, in order to calculate $\Phi=\varphi_{\mathbf{h}}+\varphi_{-\mathbf{h}}$, the simpler distribution $P(A, B)$ may be calculated instead of $P\left(A^{+}, A^{-}, B^{+}, B^{-}\right)$, as has
been done in ncs space groups (Hauptman, 1982; Giacovazzo, 1983).

The distribution $P(A, B)$ in cs crystals when dispersive atoms are present has been determined by Wilson (1980):

$$
\begin{align*}
P(A, B) \simeq & (2 \pi \delta)^{-1} \\
& \times \exp -\left(\beta^{2} A^{2}-2 \gamma A B+\alpha^{2} B^{2}\right) /\left(2 \delta^{2}\right) \tag{1}
\end{align*}
$$

where

$$
\begin{aligned}
& \alpha^{2}=\frac{1}{2}\left(\sum_{+}+\sum_{-}\right)=\varepsilon \sum_{j=1}^{N} f^{\prime 2} \\
& \beta^{2}=\frac{1}{2}\left(\sum_{+}-\sum_{-}\right)=\varepsilon \sum_{j=1}^{N} f_{j}^{\prime \prime 2} \\
& \gamma=\varepsilon \sum_{j=1}^{N} f_{j}^{\prime} f_{j}^{\prime \prime}, \quad \delta=\left(\alpha^{2} \beta^{2}-\gamma^{2}\right)^{1 / 2}
\end{aligned}
$$

From (1) Wilson derived the marginal distribution function

$$
\begin{align*}
P(|F|) \simeq & (|F| / \delta) \exp \left[-\sum_{+}|F|^{2} /\left(4 \delta^{2}\right)\right] \\
& \times I_{0}\left[S|F|^{2} /\left(4 \delta^{2}\right)\right] \tag{2}
\end{align*}
$$

where

$$
S=\left[\left(\alpha^{2}-\beta^{2}\right)^{2}+4 \gamma^{2}\right]^{1 / 2} .
$$

For non-zero $\delta$ the distribution (2) behaves quite differently from the distribution for a non-dispersive cs crystal and reduces to this when $\delta$ goes to zero. The conditional distribution $P(\varphi||F|)$ was not derived by Wilson: however, it may readily be derived by (1). We obtain

$$
\begin{equation*}
P\left(\varphi||F|) \simeq\left[2 \pi I_{0}(Z)\right]^{-1} \exp [z \cos (2 \varphi-\psi)]\right. \tag{3}
\end{equation*}
$$

where

$$
\begin{equation*}
Z=|F|^{2} S /\left(4 \delta^{2}\right) \tag{4}
\end{equation*}
$$

and $\tan \psi=2 \gamma / \sum_{-}$.
Equation (3) is a bimodal von Mises distribution with maxima at $\varphi=\psi / 2$ and $\psi / 2+\pi$. Also the distribution $P\left(\Phi||F|)\right.$ where $\Phi=\varphi^{+}+\varphi^{-}=2 \varphi^{+}$is of interest:

$$
\begin{equation*}
P\left(\Phi||F|) \simeq\left[2 \pi I_{0}(Z)\right]^{-1} \exp [Z \cos (\Phi-\psi)] .\right. \tag{5}
\end{equation*}
$$

If $|F|$ is replaced by the normalized modulus $R$, then (5) may be written

$$
\begin{equation*}
P(\Phi \mid R) \simeq\left[2 \pi I_{0}\left(Q_{c}\right)\right]^{-1} \exp \left[Q_{c} \cos (\Phi-\psi)\right] \tag{6}
\end{equation*}
$$

where $Q_{c}=\left(R^{2} \sum_{+} S\right) /\left(4 \delta^{2}\right)$.
If (6) is compared with the distribution $P(\Phi)$ in the case of anomalous diffraction for ncs crystals [see equation (5) in Giacovazzo, 1983] it may be seen that:
(a) both cs and ncs distributions are of von Mises type;
(b) both of them reach their maximum at $\psi$;
(c) $Q_{c}=Q / 2$. This result should explain why the estimation of $\left|F^{\prime \prime}\right|$ by means of equation (6) in the paper by Cascarano \& Giacovazzo (1985) is more accurate in ncs space groups than in cs ones.

## 3. The estimation of $\Phi=\varphi_{\mathrm{h}}+\varphi_{-\mathrm{h}}$ in non-centrosymmetric crystals when $\Phi$ is a symmetry-restricted phase

In a non-dispersive structure let $\varphi_{\mathrm{h}}$ be a phase restricted (because of symmetry) to $\varphi_{r}$ and let $\mathbf{C}_{r}=\left(\mathbf{R}_{r}, \mathbf{T}_{r}\right)$ be the symmetry operator for which $\mathbf{h R}=-\mathbf{h}$ (then $\left.\varphi_{r}=\pi \mathbf{h} \mathbf{T}_{r}+n \pi\right)$. When dispersive atoms are present the contribution to $F_{\mathrm{h}}$ from the real part of the scattering factors will still be restricted to $\varphi_{r}$, while, because of the supplementary contribution from the imaginary part of the scattering factors, $\varphi_{\mathrm{h}}$ may deviate from $\varphi_{r}$. Since

$$
\begin{gathered}
F_{\mathbf{h}}=\sum_{j=1}^{t}\left(f_{j}^{\prime} \xi_{j}-f_{j}^{\prime \prime} \eta_{j}\right)+i \sum_{j=1}^{t}\left(f_{j}^{\prime} \eta_{j}+f_{j}^{\prime \prime} \xi_{j}\right), \\
F_{-\mathbf{h}}=\sum_{j=1}^{t}\left(f_{j}^{\prime} \xi_{j}+f_{j}^{\prime \prime} \eta_{j}\right)+i \sum_{j=1}^{i}\left(-f_{j}^{\prime} \eta_{j}+f_{j}^{\prime \prime} \xi_{j}\right),
\end{gathered}
$$

$F_{\mathrm{h}}$ and $F_{-\mathrm{h}}$ are not the complex conjugates of each other but the identity $\left|F_{h}\right|=\left|F_{h}\right|$ still holds. Accordingly we can limit ourselves to calculate the joint probability distribution $P(A, B)$. We obtain

$$
\begin{align*}
P(A, B) \simeq & \left(2 \pi \delta^{\prime}\right)^{-1} \exp \left[-\left(\beta^{\prime 2} A^{2}\right.\right. \\
& \left.\left.-2 \gamma^{\prime} A B+\alpha^{\prime 2} B^{2}\right) /\left(2 \delta^{\prime 2}\right)\right] \tag{7}
\end{align*}
$$

where

$$
\begin{align*}
\alpha^{\prime 2} & =\frac{1}{2} \sum_{+}+\frac{1}{2} \sum_{-} \cos 2 \pi \mathbf{h} \mathbf{T}_{r}-\gamma \sin 2 \pi \mathbf{h} \mathbf{T}_{r}  \tag{8a}\\
\beta^{\prime 2} & =\frac{1}{2} \sum_{+}-\frac{1}{2} \Sigma_{-} \cos 2 \pi \mathbf{h} \mathbf{T}_{r}+\gamma \sin 2 \pi \mathbf{h} \mathbf{T}_{r}  \tag{8b}\\
\gamma^{\prime} & =\gamma \cos 2 \pi \mathbf{h} \mathbf{T}_{r}+\frac{1}{2} \sum_{-} \sin 2 \pi \mathbf{h} \mathbf{T}_{r} . \tag{8c}
\end{align*}
$$

From (7) the marginal distribution

$$
\begin{align*}
P(|F|) \simeq & \left(|F| / \delta^{\prime}\right) \exp \left[-\sum_{+}|F|^{2} /\left(4 \delta^{\prime 2}\right)\right] \\
& \times I_{0}\left[S^{\prime}|F|^{2} /\left(4 \delta^{\prime 2}\right)\right] \tag{9}
\end{align*}
$$

is readily found, where

$$
\begin{aligned}
& \delta^{\prime}=\left(\alpha^{\prime 2} \beta^{\prime 2}-\gamma^{\prime 2}\right)^{1 / 2} \\
& S^{\prime}=\left[\left(\alpha^{\prime 2}-\beta^{\prime 2}\right)^{2}+4 \gamma^{\prime 2}\right]^{1 / 2} .
\end{aligned}
$$

From definitions (8) it may be seen that $S^{\prime} \equiv S$ and $\delta^{\prime} \equiv \delta$, so that (9) coincides with (2). It may be concluded that the distribution $P(|F|)$ in ncs dispersive crystals for symmetry-restricted reflexions coincides with the distribution $P(|F|)$ in cs dispersive crystals.
From (7) the conditional distribution

$$
\begin{equation*}
P\left(\varphi||F|) \simeq\left[2 \pi I_{0}(Z)\right]^{-1} \exp \left[Z \cos \left(2 \varphi-\psi^{\prime}\right)\right]\right. \tag{10}
\end{equation*}
$$

arises, where

$$
\begin{equation*}
\cos \psi^{\prime}=\left(\alpha^{\prime 2}-\beta^{\prime 2}\right) / S, \quad \sin \psi^{\prime}=2 \gamma^{\prime} / S \tag{11}
\end{equation*}
$$

Equation (10) may be considered a generalization of (5): indeed, if $\pi \mathrm{hT}_{r}=n \pi$, then $\alpha^{\prime 2}=\alpha^{2}, \beta^{\prime 2}=\beta^{2}$, $\gamma^{\prime 2}=\gamma^{2}$.
The distribution of $\Phi=\varphi_{\mathbf{h}}+\varphi_{-\mathbf{h}}$ may be calculated by considering that $\varphi_{h}+\varphi_{-h}=2\left(\varphi_{h}-\varphi_{r}\right)$. After a straightforward change of variable (10) becomes

$$
\begin{align*}
P(\Phi||F|) \simeq & {\left[2 \pi I_{0}(Z)\right]^{-1} } \\
& \times \exp \left[Z \cos \left(\Phi+2 \varphi_{r}-\psi^{\prime}\right)\right] . \tag{12}
\end{align*}
$$

By means of (11) it may be found that

$$
\cos \left(2 \varphi_{r}-\psi^{\prime}\right)=\sum_{-} / S \quad \text { and } \quad \sin \left(2 \varphi_{r}-\psi^{\prime}\right)=2 \gamma / S
$$

so that

$$
\tan \left(2 \varphi_{r}-\psi^{\prime}\right)=\tan \psi
$$

Equation (12) is therefore identical to (5): it may be
concluded that $P(\Phi||F|)$ is the same both for cs crystals and for restricted-phase reflexions in ncs crystals.

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# Least-Squares Absolute-Structure Refinement. A Case Study of the Effect of Absorption Correction, Data Region, Stability Constant and Neglect of Light Atoms 

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#### Abstract

X-ray diffraction intensity data measured on two fourcircle diffractometers from a crystal of the compound potassium hydrogen ( $2 R, 3 R$ )-tartrate have been used to study the effect of absorption correction, data region, stability constant and neglect of light atoms in the atomic model on the least-squares estimate of the absolute-structure (inversion-twin) parameter $x$. It is shown that for a complete data set with Friedel pairs measured in the same plane of diffraction, an absorption correction reduced the e.s.d. of $x$ without significantly altering its value. For data sets where only one member of each Friedel pair is allowed to contribute in the least-squares analysis, e.s.d.'s and deviations of $x$ from its ideal value are increased compared with complete data sets containing both members of each Friedel pair. Certain aspects of combining a complete data set consisting of one asymmetric unit of reciprocal space with all-sphere measurements of absolute-structure-sensitive reflections have also been investigated. Lowering the value of the stability constant increases the e.s.d. of $x$,


produces values of $x$ closer to its ideal value for complete data sets and increases the variability of $x$ for incomplete data sets. Neglect of hydrogen atoms from the atomic model produces a very small but quantifiable shift in the estimated value of $x$.

## Introduction

In previous work (Flack, 1983; Bernardinelli \& Flack, 1985) it has been shown that absolute structure may be determined very efficiently by assuming any noncentrosymmetric crystal to be an inversion twin and letting the absolute-structure (inversion-twin) parameter $x$ be a variable in the least-squares refinement. Whereas a great deal is known about the bias that may be caused in least-squares-estimated atomic positional and displacement parameters due to systematic effects such as absorption, thermal diffuse scattering, extinction, scan-range truncation etc., little at present is understood of the behaviour of the absolute-structure parameter. It is the intention of this paper to present results on four systematic effects; absorption,

